Search Notes		

Applica	tion/Control No.	Applicant(s)/Patent under Reexamination	
10/664,	500	YALOVSKY,	MARK
Examin	er	Art Unit	
Maikha	nh Nguyen	2176	

SEARCHED				
Class	Subclass	Date	Examiner	
715	530	5/5/2006	мк	
715	517,519	5/5/2006	MK	
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707	100	5/5/2006	MK	
Updated	Search	11/15/2006	MK	
Updated	Search	6/13/2007	MK	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Name Search	5/5/2006	МК
West Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB)	5/5/2006	МК
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	11/15/2006	MK
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	6/13/2007	МК